

**Notice of References Cited**Application/Control No.  
10/587,315Applicant(s)/Patent Under  
Reexamination  
YAMADA ET AL.Examiner  
JUAN E. VAUGHAN IIArt Unit  
1795

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0224281 A1	12-2003	Ishizuka et al.	430/157
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	D	US-			
	E	US-			
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